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11-8-02

J. Action

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Manoj K. Jain Art Unit: 2814
Serial No.: 10/006,578 Examiner: Le, T.
Filing Date: 12/06/01 Docket No.: TI-31858
Title: PREVENTION OF CONTACT FAILURE BY HYDROGEN
TREATMENT

Amendment under 37 CFR 1.115

Assistant Commissioner of Patents
Washington, DC 20231

FAX COPY RECEIVED

OCT 31 2002

TECHNOLOGY CENTER 2800

Dear Sir:

The following amendments and remarks are offered in response to the Examiner's Office Action dated 06/05/02. They are respectfully submitted as a full and complete response to that Action.

Please amend the above-referenced application as follows:

In the Claims:

Amend claim 1 to read as follows:

1. (amended) A method of forming a conductive structure in an integrated circuit, comprising the steps of:
 forming a dielectric layer over a semiconductor body;
b1
 forming a hole in said dielectric layer;
 forming a conductive liner in said hole;
 annealing said conductive liner;
 treating said conductive liner with hydrogen;
 forming a conductive barrier over said conductive liner; and